



TEST / CALIBRATION REPORT

EMC / EMI Test Report for MECO Voltage Transducer

Testing as per BS EN 61326 (Edition 1998)



ELECTRONICS REGIONAL TEST LABORATORY (WEST)
MINISTRY OF COMMUNICATIONS & INFORMATION TECHNOLOGY, (STQC Dte.)

Government of India

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MEMORANDUM

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2. The report shall not be regarded in any way diminishing the normal contractual responsibilities / obligations between the customer and **ERTL (W)**.
3. The result reported in this report are valid only at the time of and under the stated conditions of the measurements.

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1. SCOPE

1.1 Service Request No :ERTL(W)/20031658

1.1.1 Service Request finalised on :01- SEP - 2003

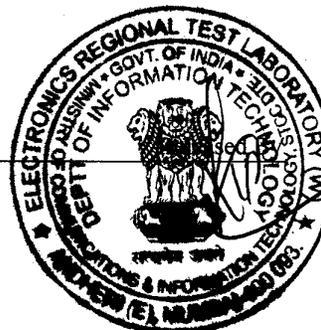
1.2 Requested by : MECO INSTRUMENTS PVT. LTD.
(Name and address of manufacturer) 301,BHARAT INDUSTRIAL
ESTATE,T.J.ROAD,SEWREE,MUMBAI-400 015

1.3 Item No.	Description	Qty	Manufacturer and Type No.	Serial No
1.	VOLTAGE TRNSDUCER	01	MECO INSTRUMENTS PVT. LTD./ VMT	30932

1.4 Test specifications BS EN 61326 (Edition 1998)

1.5 Lab Ambient Temperature : (25 +_2) deg.C
Humidity : (55 +_5) % RH

- 1.6 Test Equipment used :
1. EMI/034 : RS Chamber (Keytek, G-Strip)
 2. EMI/036 : RF Signal Generator (HP, 8648 A) for C.S and R.S tests
 3. EMI/037 : RF Amplifier (AR, 25A100) for R.S test
 4. EMI/044 : Three Phase Immunity Test System
 5. CPU/064 : EMI receiver (HP8568B) for CE and RE test
 6. EMI/048 : ESD Gun for ESD test
 7. ----- : Biconical & Log periodic antennae.
 8. EMI/033 : EFT Simulator
 9. EMI/034 : Coupling / De coupling Network
 10. CPU/066 : LISN



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2.0 EQUIPMENT UNDER TEST (EUT)

2.1 Description

EUT is an VOLTAGE TRANSDUCER.

2.2 Operating modes during normal testing.

The output of EUT shall be loaded with full rated resistive load for normal operations & all applicable tests. The output current shall remain in the range of 0 to 10 mA DC at output 1 & in the range of 4 to 20 mA DC for output 2, during after & before all tests. EUT was made operational with rated input voltage & output was loaded with resistive load during immunity tests.

2.3 Functional check for all immunity tests.

The functional check for all immunity tests of EUT is to observe output current across the resistive load for O/P 1 & O/P 2.



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3.0 Test Results

3.2 RADIATED EMISSION

Test Rationale: To measure emissions of the EUT radiated into space and to compare them with specified limits to ascertain that the EUT will not disturb other equipment by generating such emissions above a certain limit.

a) Test Condition:

Set-up As per BS EN 55022, CLASS 'A'
 Frequency Range 30 MHz – 1000MHz
 EUT in normal operating condition as per Sr. No. 2.2

b) Receiver:

Bandwidth 120 KHz
 Detectors QP
 Antenna Bi-Conical (For 30 – 200 MHz)
 Log-Periodic (For 200 – 1000 MHz)
 Configuration Conforming to CISPR 16-1& CISPR 16-2

c) Test procedure

- Ambient measurements carried out first with EUT "off" and peaks noted
- EUT was switched "ON" and Emission peaks noted.
- Antenna height and position were changed to maximize Emissions.
- A table of Emission and corresponding Ambient was then drawn up.
- "Ambient" and "Emission" peaks were compared. Peaks with a difference of less than 5 dB were discarded.

d) Requirements

EUT emissions shall be below following limits

Freq. (MHz)	Limits (dBuV/m)
30-230	QP
230-1000	50
	57

e) Observations

For results pl. refer page 9 of 9.

f) Results

Complied



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3.3 RADIATED SUSCEPTIBILITY (RS)

Test Rationale: To check immunity characteristics of the EUT in the presence of radiated fields generated by intentional emitters like Radio /TV transmitters, wireless equipment and the like by illuminating the EUT by such frequency

- a) **Test Condition:**
 - Set-up As per BS EN 61000-4-3 (Edition – 1995)
 - Frequency Range 80 MHz – 1000 MHz
 - Field Strength 10 V/m
 - Simulation Using G – STRIP chamber
 - EUT in normal operating condition as per Sr. no. 2.2.

- b) **Test procedure**
EUT enclosure was exposed to radiated field strength in G strip chamber for the above subject frequency range. EUT performance was observed during and after the test as per Sr. No. 2.3

- c) **Requirements**
Normal performance of EUT shall be within the specifications as per Sr. No. 2.3.
Performance criterion A

- d) **Observations**
Operation normal as per Sr. No. 2.3 during and after the test. No deviation from actual operating condition could be observed.

- e) **Results**
Complied



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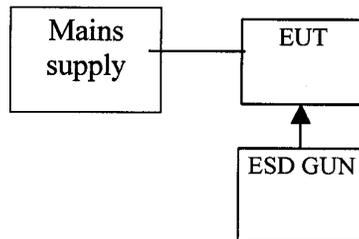
3.4 ELECTROSTATIC DISCHARGE (ESD)

Test Rationale: To check immunity characteristics of the EUT against Discharge of Static Electricity that may occur when a charged operator touches the EUT.

a) Test Condition:

- Set-up** As per BS EN 61000-4-2 (Edition 1995)
- Mode of simulation:** Contact Discharge on conductive surfaces & Air Discharge on non- conductive surfaces
- Test Voltage:** **Contact Discharge:** 4kV
Air Discharge: 8kV
- No. of Discharges** 10
- Polarity** Positive and Negative
- Points of Discharge** **Contact Discharge**
Contact screws
Air Discharge:
On the Insulated surfaces
- Simulation** Using ESD Gun
- EUT in normal operating condition as per Sr. no. 2.2

b) Test procedure:



- EUT initially subjected to indirect discharge on VCP and HCP.
- EUT was then screened in continuous discharge mode.
- At susceptible points, ten single discharges were applied.

c) Requirement:

During testing, temporary degradation or loss of function or performance is allowed which is self-recoverable. Performance criterion B

d) Observations

Operation of the EUT was found normal during and after the test as per Sr. No. 2.3

e) Results
Complied



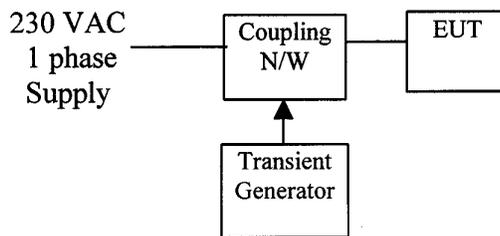
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3.6 ELECTRICAL FAST TRANSIENTS (EFT)

Test Rationale: To check immunity characteristics of the EUT against transients generated by inductive load switching, Relay contact bouncing, switching of high voltage switchgear and the like

- a **Test Condition:**
 - Set-up** As per BS EN 61000-4-4 (Edition 1995)
 - Pulse** 5/50 ns
 - Modes** Common and Differential
 - Test Level** 3
 - Pulse Amplitude** 2 kV
 - Pulse Rep. Rate** 5 kHz
 - Polarity** Positive and Negative
 - Duration of test in each mode** 60 s
 - Simulation** On 230 V single phase AC supply lines by Direct Injection
EUT in normal operating condition as per Sr.No. 2.2

c **Test procedure:**



➤ Transients generated by the generator were coupled to the 230 VAC Supply through a coupling N/W .

- d **Requirements :**
During testing, temporary degradation or loss of function or performance is allowed which is self-recoverable. Performance criterion B
- e **Observations**
Operation of the EUT was found to be normal as per Sr. No. 2.3 during and after the test.
- f **Results**
Complied



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3.3 Conducted susceptibility

Test Rationale:

To check immunity characteristics of the EUT against Conducted RF Susceptibility levels.

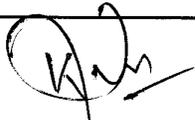
- a) **Test Condition:**
 - Set-up** As per BS EN 61000 – 4 –6 (Edition 1996)
 - Mode of simulation:** Injected on power mains
 - Test Voltage:** 3 V r.m.s
 - Simulation** Using coupling/ decoupling Network
EUT in normal operating condition as per Sr. No. 2.2
- c) **Test procedure:**
 - Conducted RF level was injected to power mains by coupling/ decoupling network along the subject frequency range & EUT performance was monitored during and after the test as per Sr. No. 2.3
- d) **Requirement:**
 - Performance Criterion 'A', Normal Operation of the EUT with specified performance as per Sr. No. 2.3
- e) **Observations**
 - Operation of the EUT was found normal during and after the test as per Sr. No. 2.3
- f) **Results**
 - Complied



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4.0 General Remarks : Nil

REPORT APPROVED BY


 HEAD (EMI/PCT)



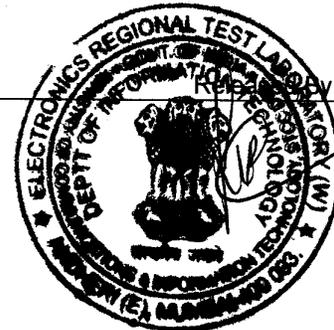
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Radiated Emission Test Results

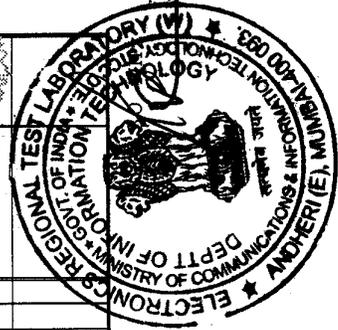
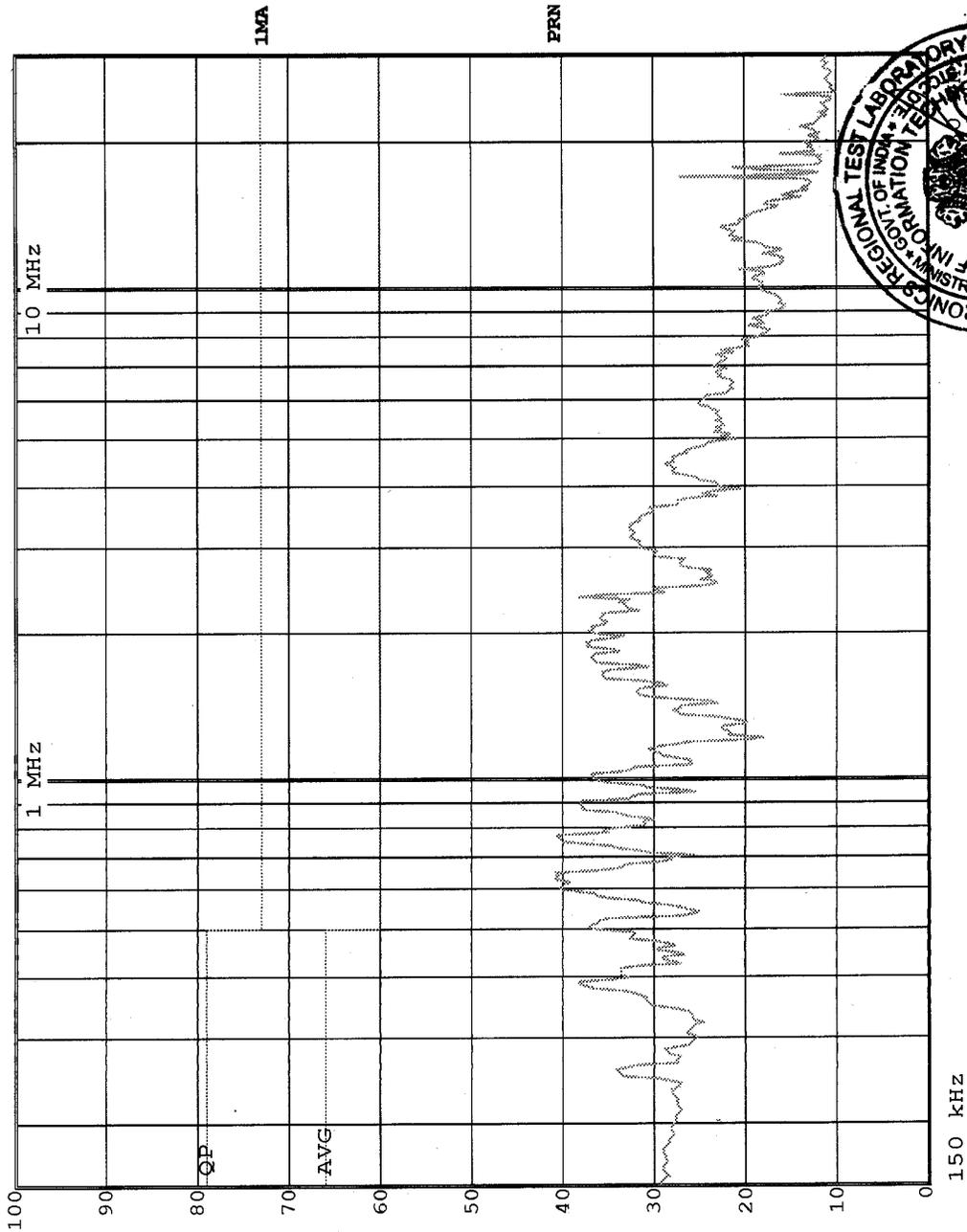
SR.NO.	FREQUENCY (MHz)	EMISSIONS OBSERVED (dBuV/m)	LIMITS (dBuV/m)	REMARKS
1.	49.60	40.50	50.00	Pass
2.	51.91	45.95	50.00	Pass
3.	63.32	31.40	50.00	Pass
4.	83.41	20.00	50.00	Pass

Testing has been carried out at 3- meter test distance and limits have been modified accordingly.



4.6 JAN 2004

Marker 1 [T1] Det AV Trd
 16.21 dBuV ResBW 9 kHz
 INPUT 2 8.18200000 MHz Meas T 100 ms Unit dBuV
 Att 10 dB



Date: 24.DEC.2003 16:47:48

OUR ACCREDITATION STATUS

ERTL (W) set up under the STQC Directorate, Ministry of Communications & Information Technology, Govt. of India has been accredited under number of national / international systems as follows :

SYSTEM	AREA	STATUS
<p>IECQ (International Electro-technical Commission on Quality Assessment System for Electronic Components)</p>	<p>Component Testing</p> <ul style="list-style-type: none"> ● Resistors (Fixed) ● Capacitors (Fixed) 	<p>Accredited as ITL (Independent Test Laboratory)</p>
<p>NABL (C), India National Accredital Board for Test & Calibration laboratories (Calibration System)</p>	<p>Calibration</p> <ul style="list-style-type: none"> ● Electro-technical discipline ● Thermal discipline ● Mechanical discipline 	<p>Accredited Calibration Laboratory</p>
<p>NABL(T), India National Accredital Board for Test & Calibration laboratories (Testing System)</p>	<p>Electronic & Electrical Testing</p>	<p>Accredited Test Laboratory</p>
<p>IECEE-CE-Scheme</p>	<ul style="list-style-type: none"> ● Mains Operated Electronic Consumer Products 	<p>Approved as a CB test Laboratory</p>
<p>Other recognition</p>		<p>Recognised by CSPO of State Govt., DOT, Naval Docyard, LCSO etc.</p>